

# PACCD-2016 Conference Summary

Robert Lupton

2016-12-02

# New Astronomical Devices

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Should we be more scared or excited?

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Mostly the CMOS (including HgCdTe ROIC) talks were comfortingly familiar; just like a one-pixel CCD

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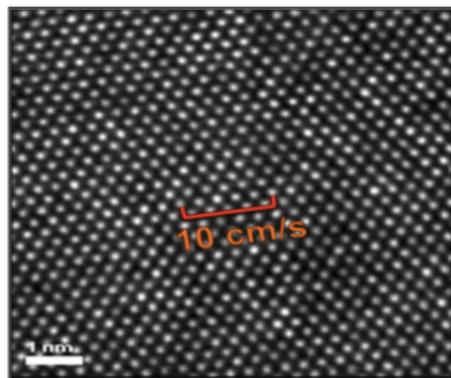
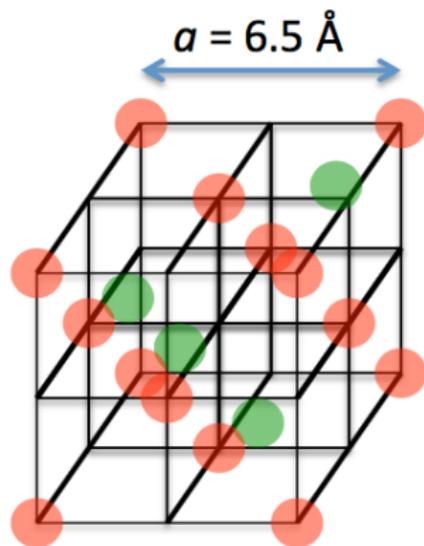
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Talk of reciprocity failure took me back to a an era that finished just before I started my PhD. I was not happy.

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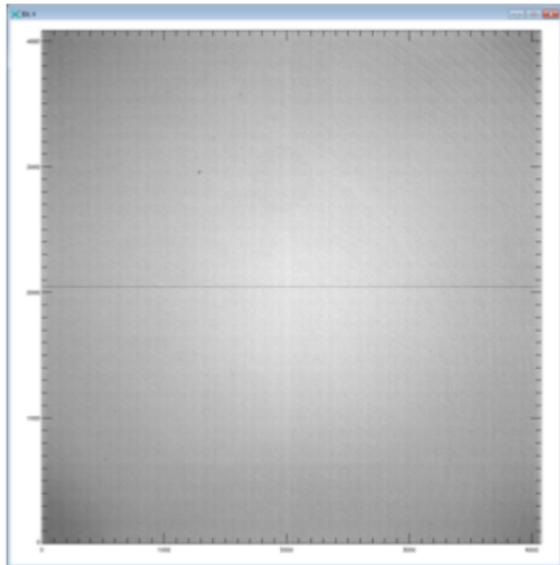
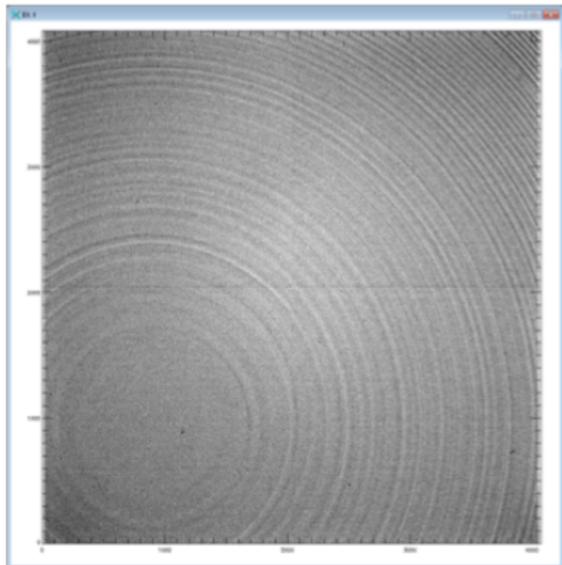
# Strategy for Systematics

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LAYER	PROCESS
<b>1</b>	<i>Eliminate the physics causing the effect (but not always possible).</i>
<b>2</b>	<i>Develop a first-principles model (but again, not always possible).</i>
<b>3</b>	<i>Develop an empirical model based on stars or external calibration data (may capture multiple pieces of physics simultaneously).</i>
<b>4</b>	<i>Mask affected data (if a small number of pixels are affected, e.g. persistence, cosmic rays ...).</i>
<b>5</b>	<i>Statistical corrections based on science galaxies (e.g. de-trending with respect to position on focal plane).</i>
<b>6</b>	<i>Cross-correlations of successive passes over the sky at different roll angles (tile 2x per filter, 3 shape measurement filters).</i>

Chris Hirata

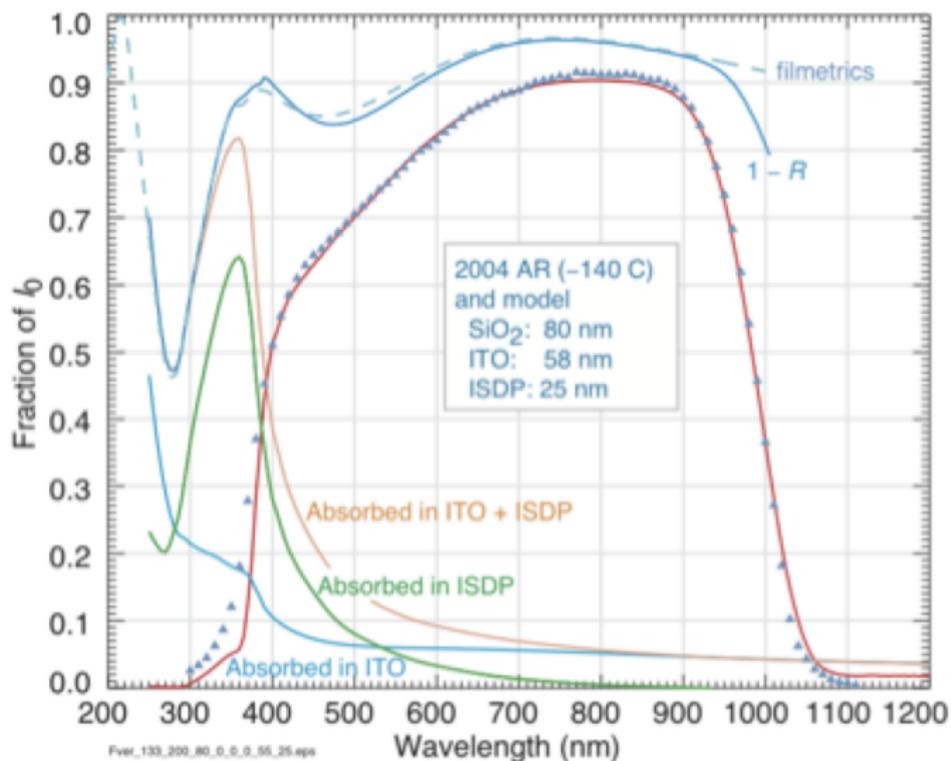
## Fix the physics [and devices]



Holland

# Fix the physics [and devices]

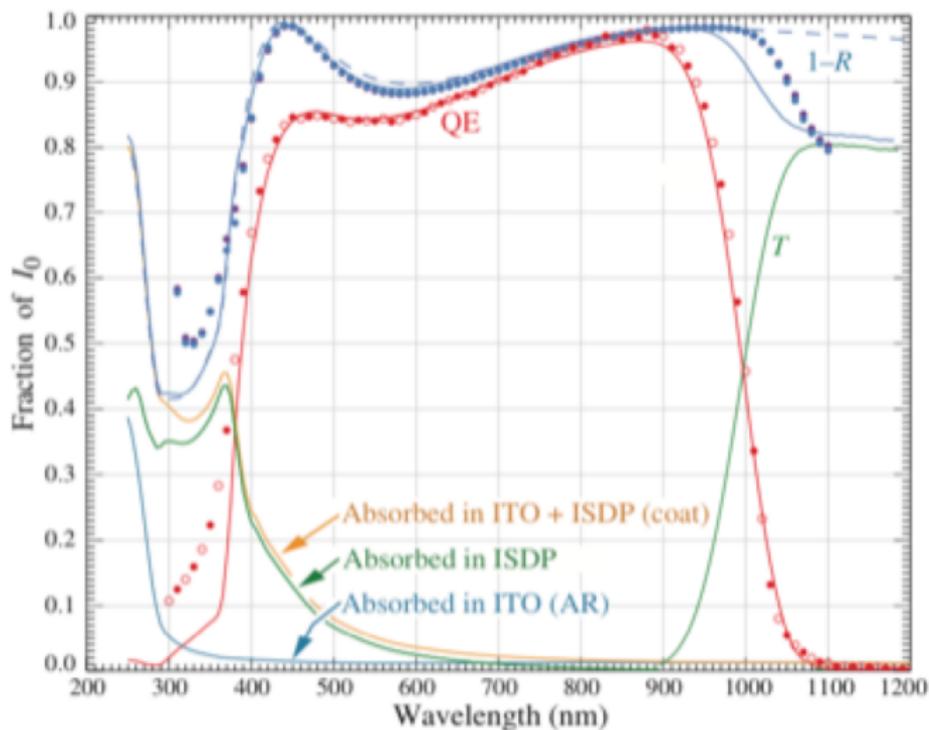
- QE results with old ITO SiO<sub>2</sub> AR coating



Holland

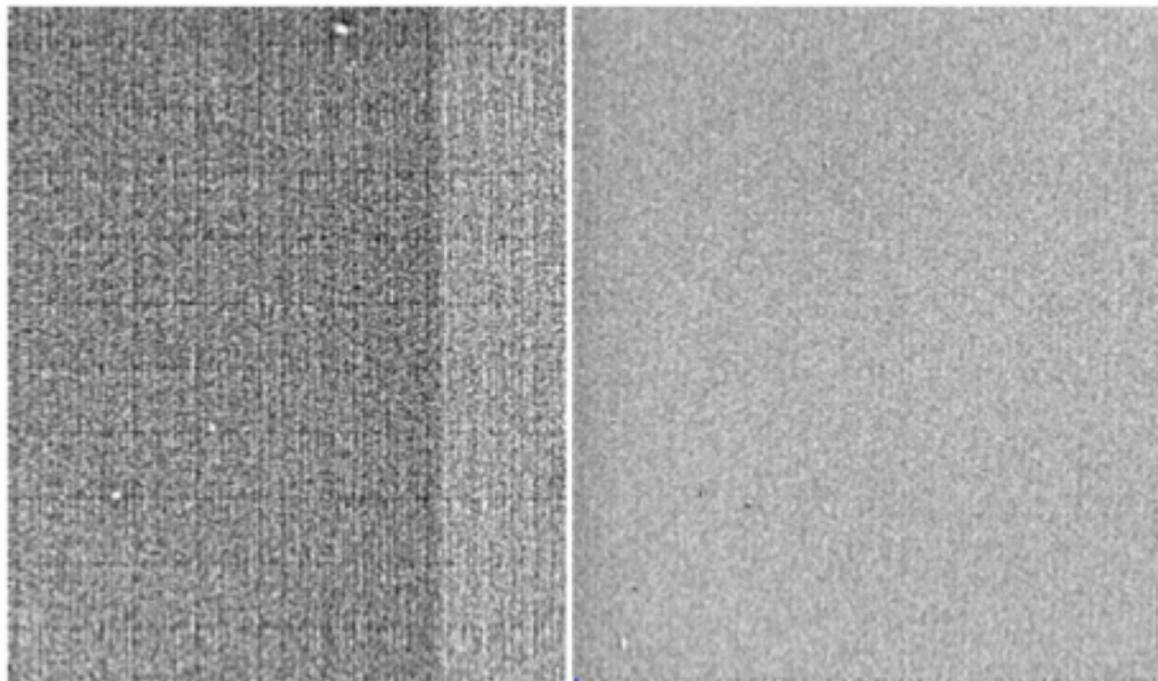
## Fix the physics [and devices]

- QE results with ITO / ZrO<sub>2</sub> / SiO<sub>2</sub> AR coat



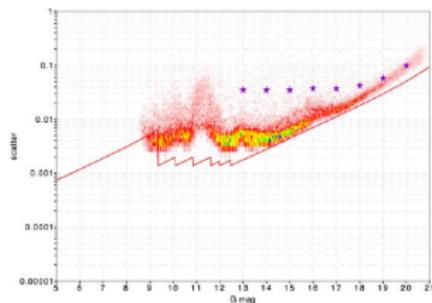
Holland

## Fix the physics [and devices]



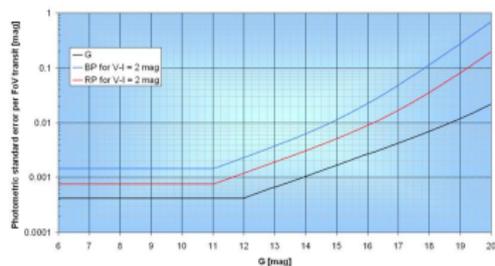
Lesser

# Fix the physics [and devices]

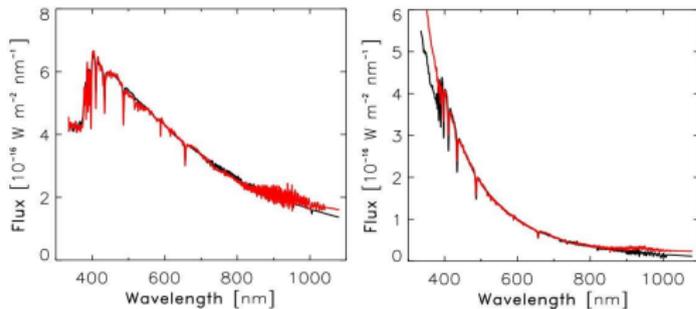


First release, 14<sup>th</sup> Sep 2016  
G passband

Second release, Q4-2017  
 $G_{XP}$  passbands

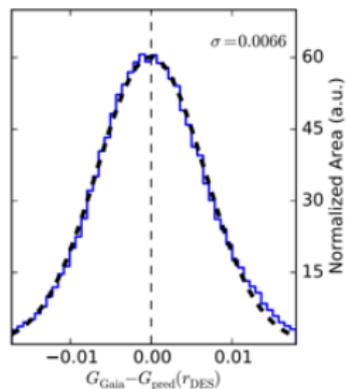
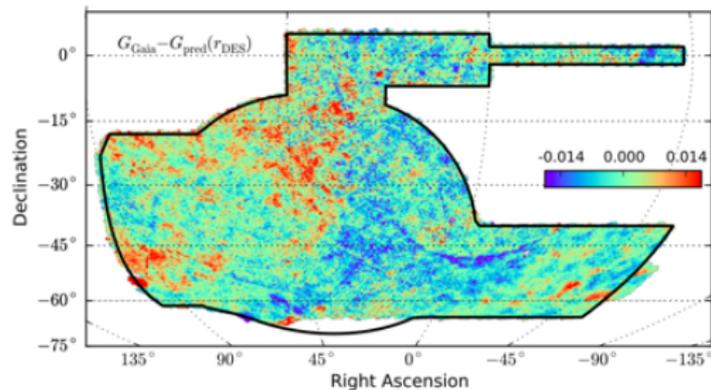


Third release 2018 (TBC)  
XP spectra



Carrasco

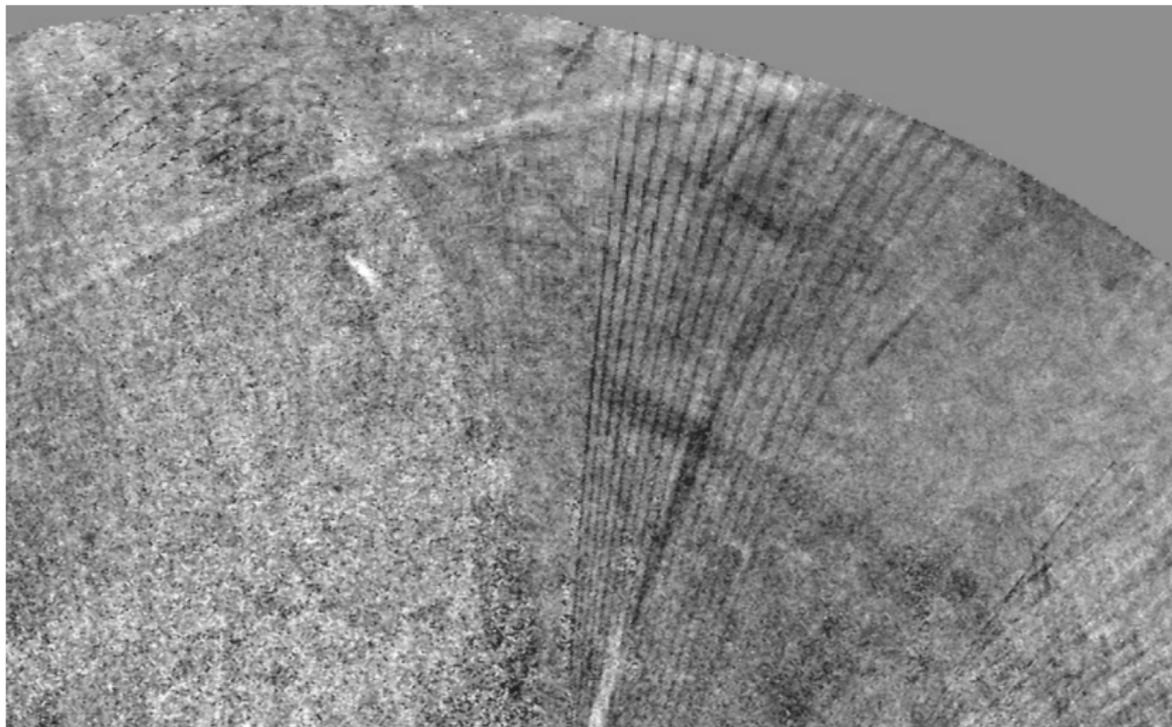
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Scolnic

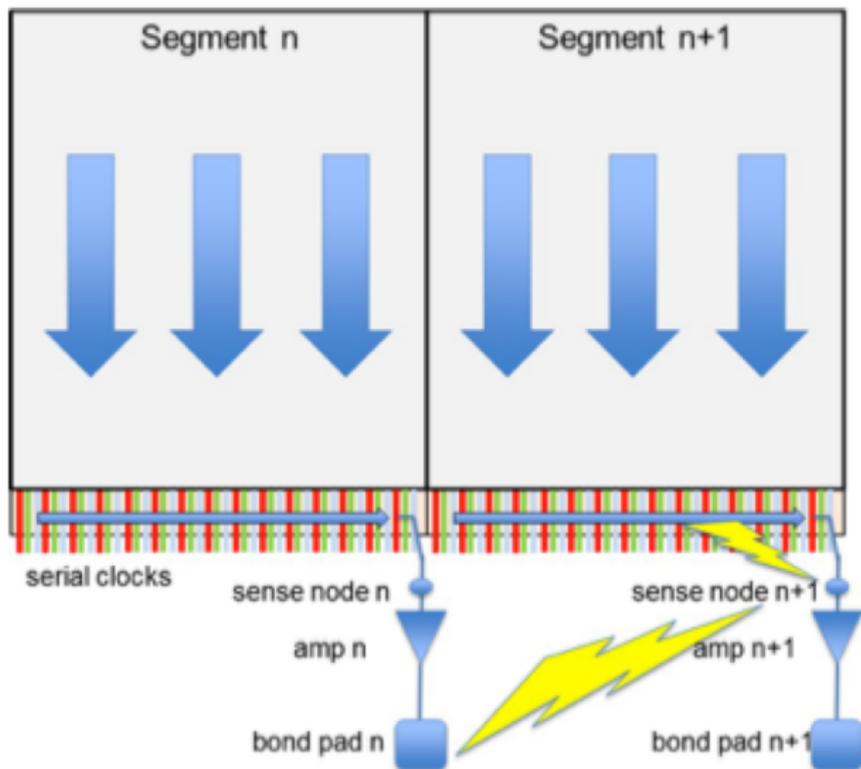
# Fix the physics [and devices]

Most residuals are Gaia stripes



Finkbeiner

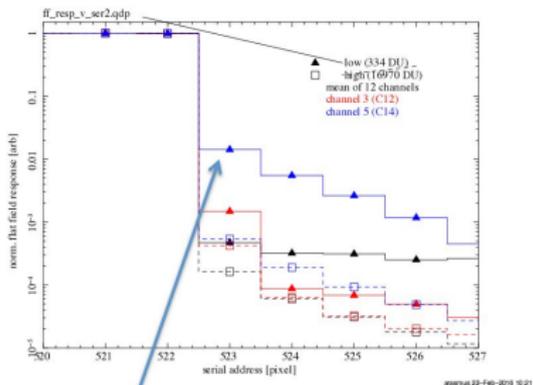
# New problems we cause ourselves



O'Connor

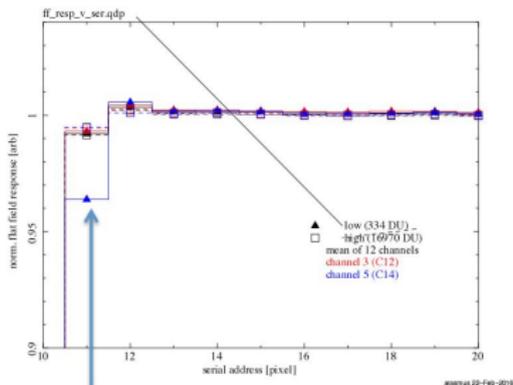
# New problems we cause ourselves

Last columns & EPER deferred charge release profile (log scale)



Integrated charge release 2.4% of flat field level p/p,  $\sim 1.1$  pixel release/de-trapping time constant

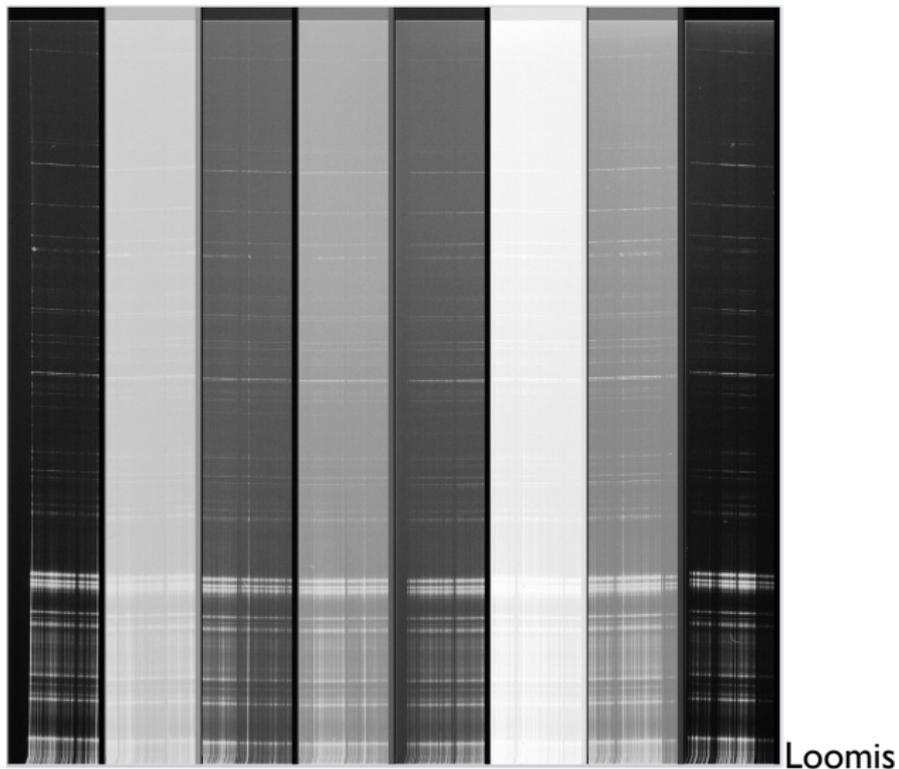
Leading columns & "leading charge loss" (linear scale)



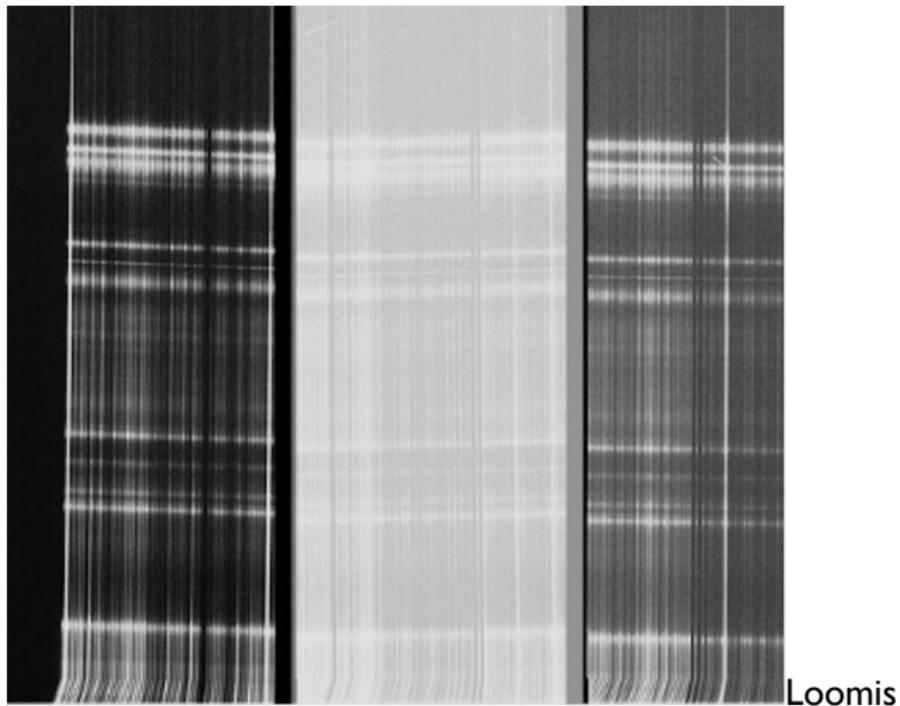
Leading signal loss is between 2.5 and 3.0% of flat field level p/p, trapping time appears to be shorter than de-trapping time

Rasmussen

# New problems we cause ourselves



# New problems we cause ourselves

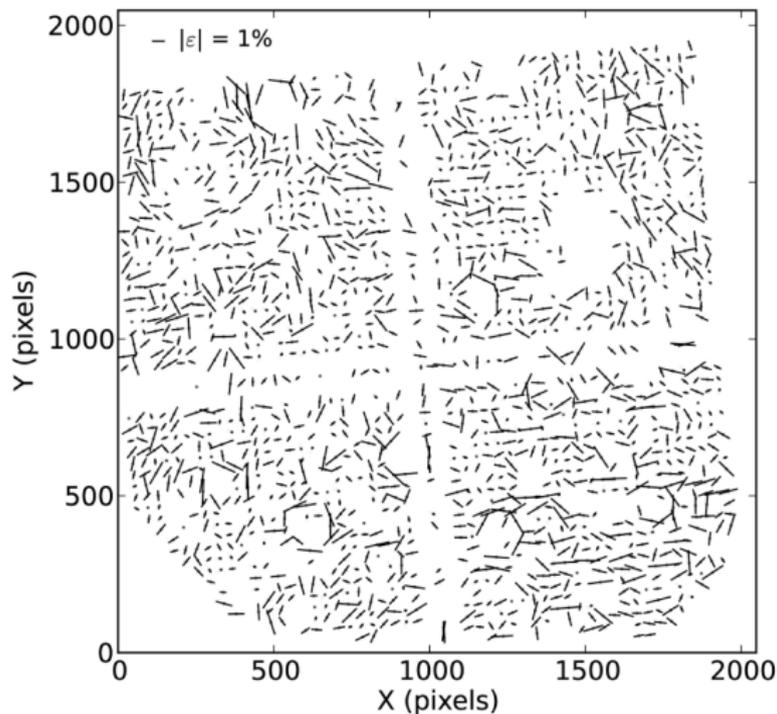


# Translation to CMOS/HgCdTe

We see effects familiar from CCDs in HgCdTe devices.

# Translation to CMOS/HgCdTe

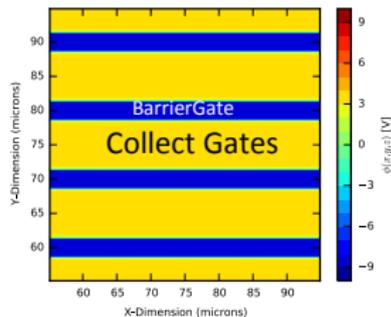
We see effects familiar from CCDs in HgCdTe devices.



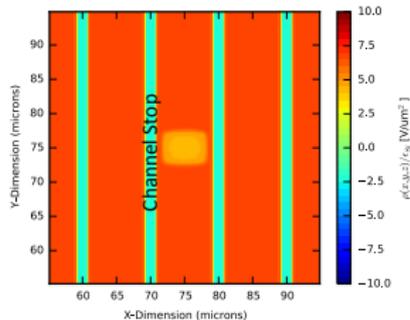
(assuming that this is some sort of pixel-size or intra-pixel sensitivity effect)

# Develop a first-principles model

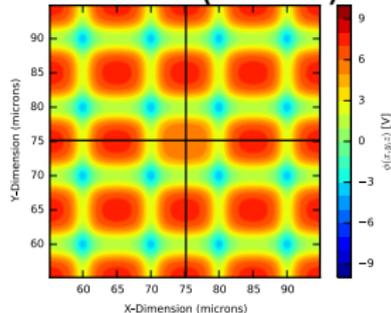
## Potential( $z=0$ )



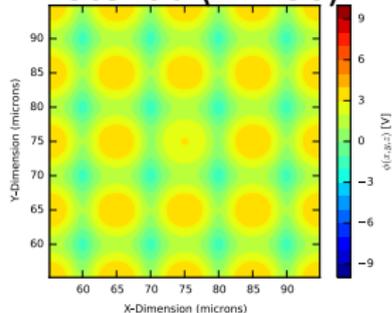
## Charges



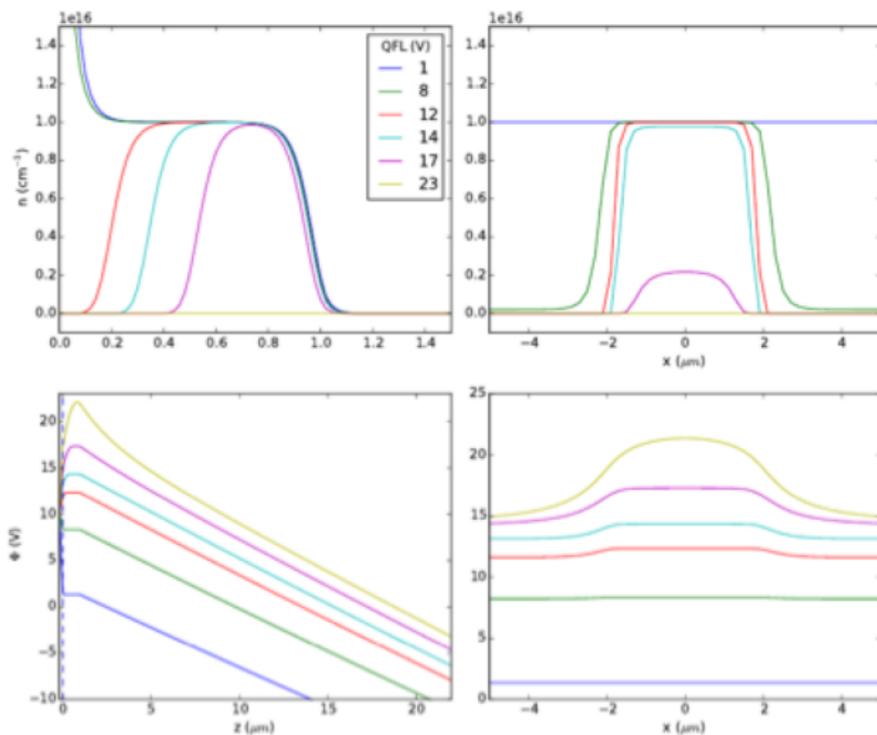
## Potential( $z=1.07$ )



## Potential( $z=2.56$ )



# Develop a first-principles model



# Develop an empirical model

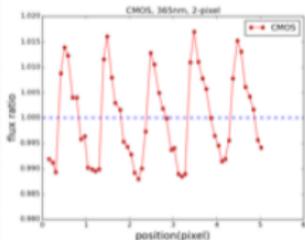
Need measurements first...

# Develop an empirical model

Need measurements first...

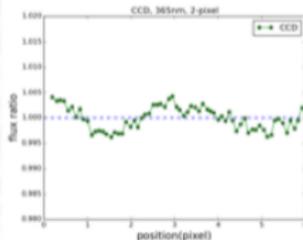
## Flux Variations for G400 & DV435

GSENSE400BSI



RMS: 0.89%

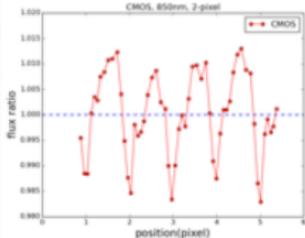
DV435: CCD47-20



RMS: 0.22%

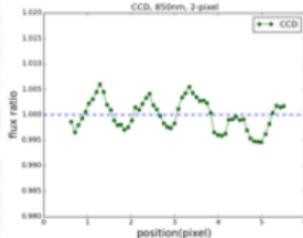
365nm

CMOS, 850nm, 2-pixel



RMS: 0.80%

CCD, 850nm, 2-pixel

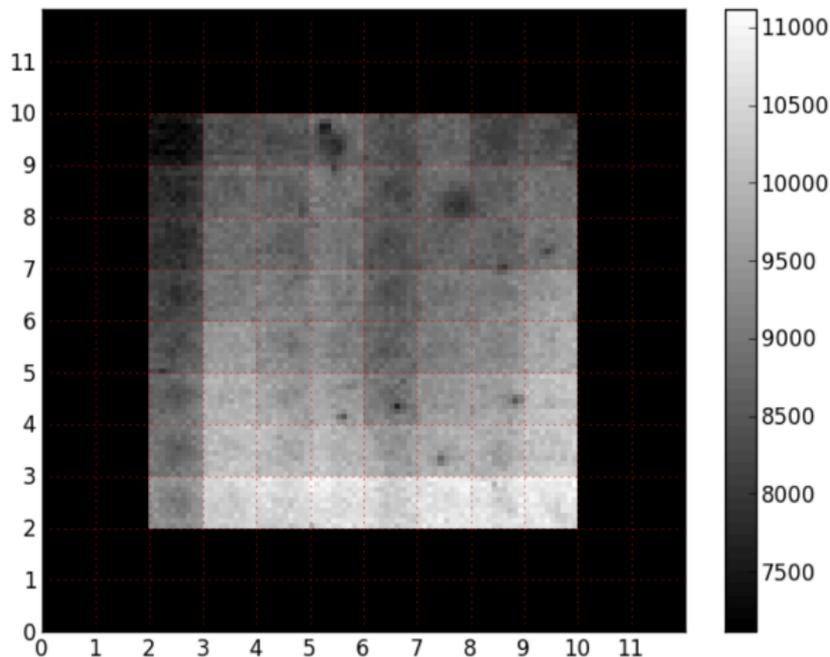


RMS: 0.20%

850nm

# Develop an empirical model

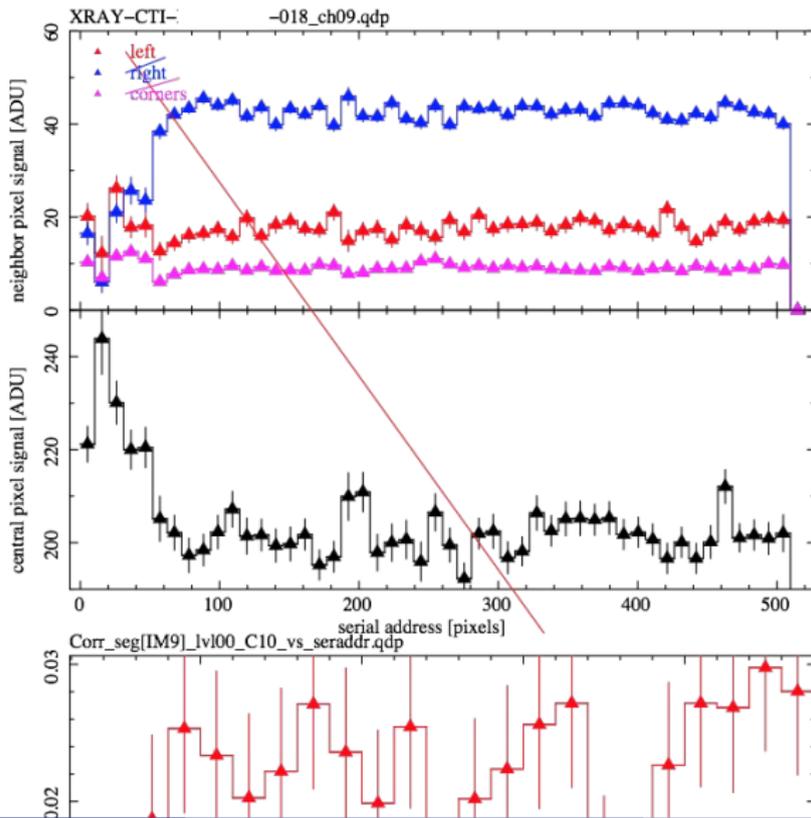
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Hardy et al. (2014)  
SPIE 9154, 9154D-12

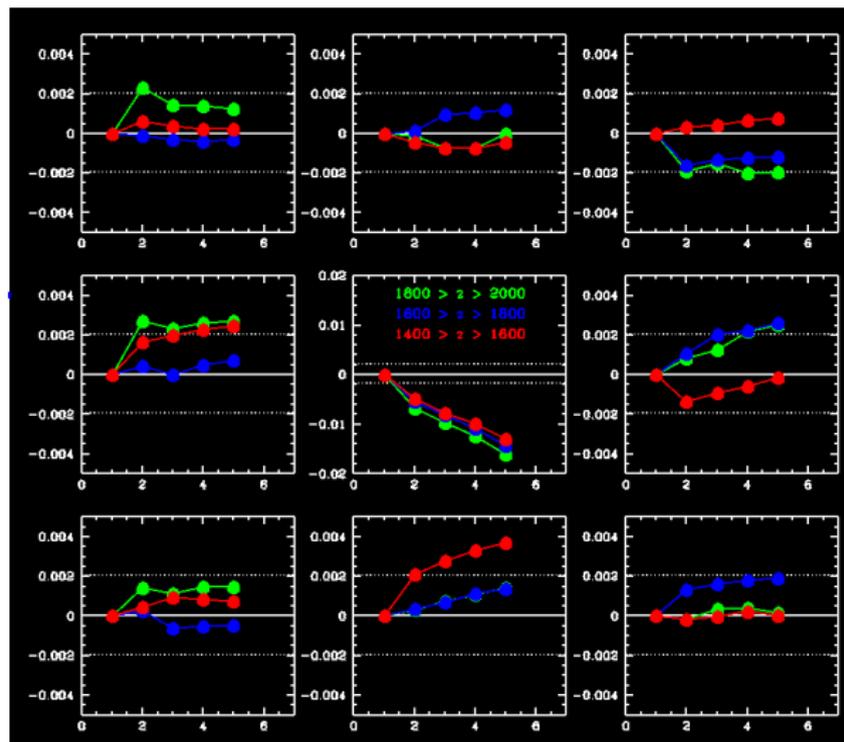
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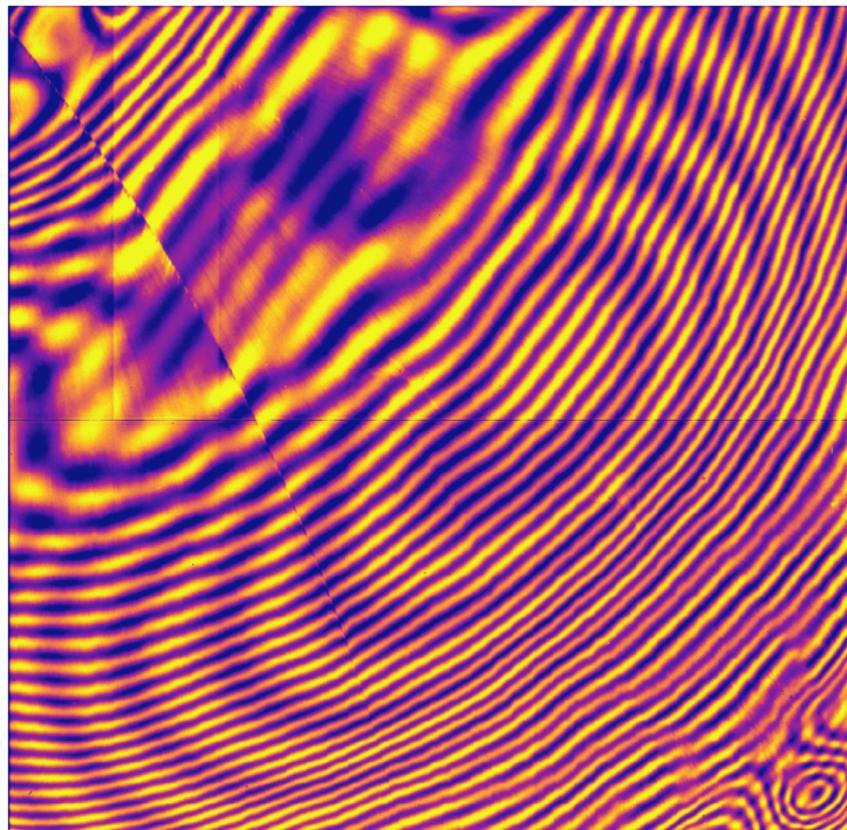
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# Calibration Instrumentation

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A CBP or DECal isn't a model, but it allows us to understand and remove pernicious effects

# Develop an empirical model

How good does the model have to be?

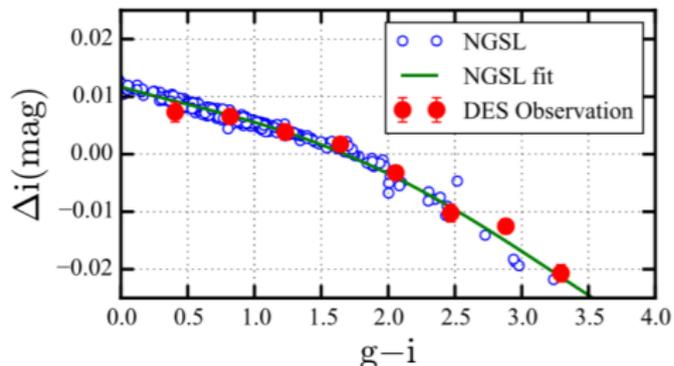
# Develop an empirical model

How good does the model have to be?

*E.g.* Chaz and Andrez's work on the importance of non-linearity for WFIRST

# Calibration Correlations

$r < 0.1R_{\max}$  vs.  $r > 0.6 R_{\max}$

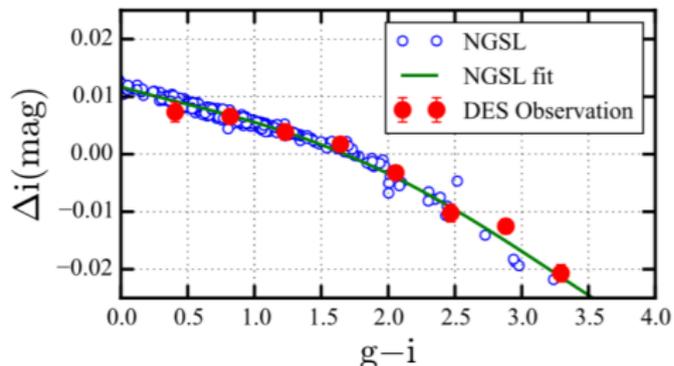


**Before correction: SCE > 20mmag**  
**After correction: SCE < 3mmag**

We can call this an empirical correlation or a model.

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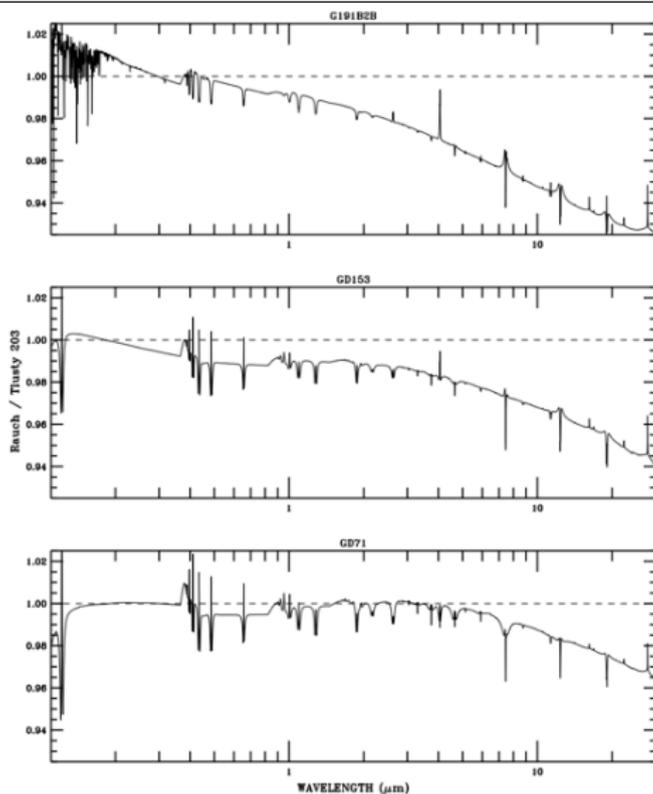
$r < 0.1R_{\text{max}}$  vs.  $r > 0.6 R_{\text{max}}$



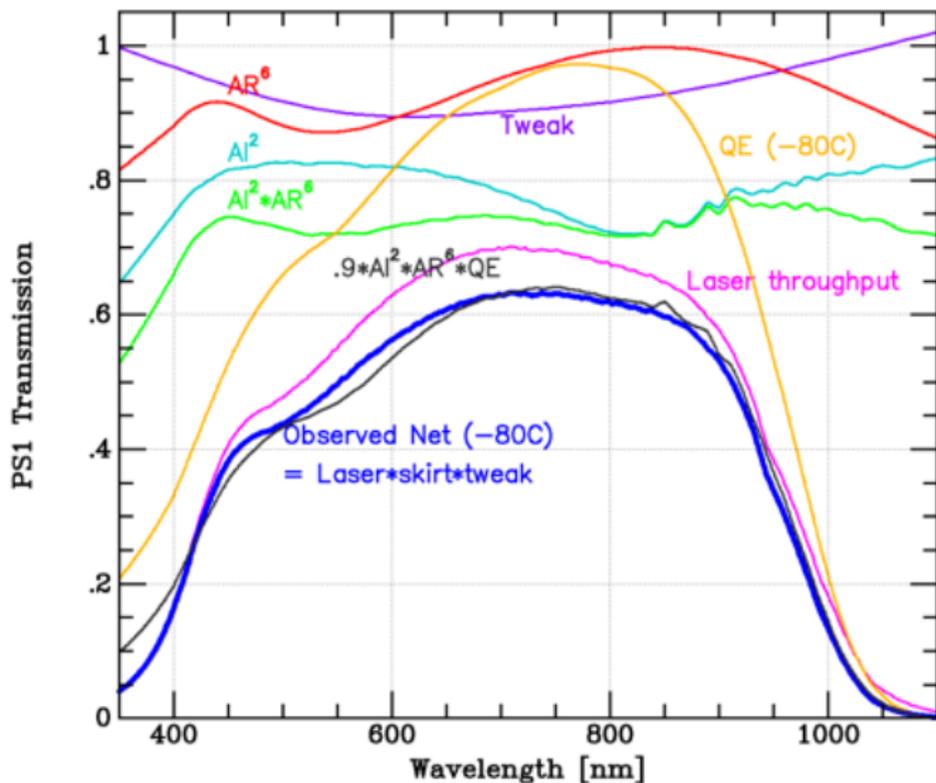
**Before correction: SCE > 20mmag**  
**After correction: SCE < 3mmag**

We can call this an empirical correlation or a model. Or one of Chris's despised statistical corrections.

# Absolute Calibration



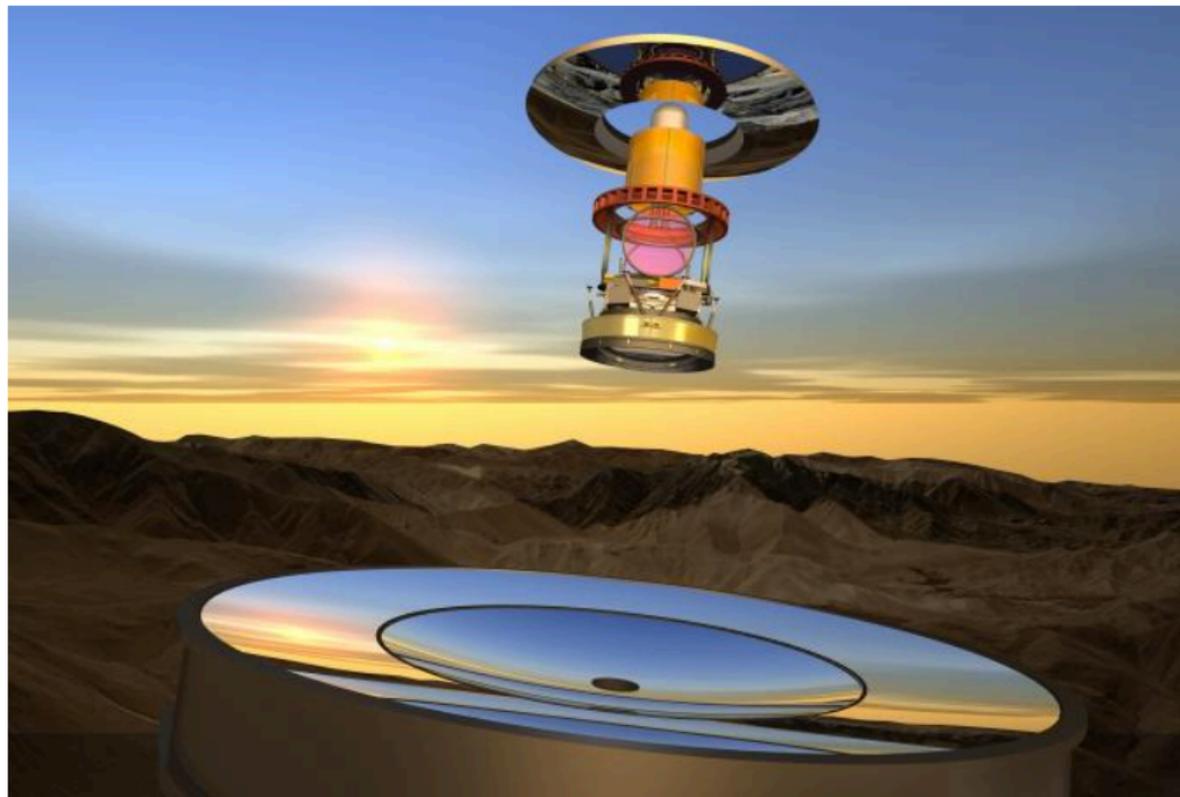
# Absolute Calibration



# Absolute Calibration



# Absolute Calibration



# New Software

Almost all of this talk implied work for authors of pipelines.

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